Abstracts

Matching Structures for High Yield Amplifier Design

J. Purviance, W. Brakensiek, D. Monteith and T. Ferguson. "Matching Structures for High Yield Amplifier Design." 1988 MTT-S International Microwave Symposium Digest 88.1 (1988 Vol. I [MWSYM]): 375-378.

Circuit yield is evaluated for the commonly used narrowband lumped and distributed parameter matching structures. It is shown that each structure has highest yield for load impedances in a given region on the Smith Chart. A simple design chart is developed which gives the designer a high yield matching structure for any given load impedance. Two examples illustrate its use.

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